

Notice of References Cited	Application/Control No. 10/619,943		Applicant(s)/Patent Under Reexamination PETERSON ET AL.	
	Examiner Kathleen S. Yuan		Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,046,109	09-1991	Fujimori et al.	382/144
*	C	US-4,578,810	03-1986	MacFarlane et al.	382/147
*	D	US-5,444,480	08-1995	Sumita, Masahiko	348/127
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Allan et al, Critical Area Extraction for Soft Fault Estimation, Febuary 1998, IEEE, Vol II, No I, pg. 1-3
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.